PAST TTTC EVENTS
6th International Symposium on Electronic Design, Test and Applications (DELTA 2011)
17–19 January 2011
Queenstown, New Zealand
http://delta.massey.ac.nz/

DELTA 2011 was the sixth in a series of very successful symposia. The symposia’s mission is to bring together researchers, engineers, and experts from all over the world to meet and discuss the latest results and cutting-edge research in the emerging area of electronic design, manufacturing, test, advanced system applications, and related areas. The 2011 keynote speech was delivered by Richard Blaikie, professor (microelectronics and nanofabrication), Department of Electrical and Computer Engineering, Canterbury University, New Zealand. The conference program was spread over three days and 13 different sessions.

IEEE 19th Asian Test Symposium (ATS 2010)
1–4 December 2010
Shanghai, China
http://ats10.shu.edu.cn/

ATS 2010 was the 19th in this series of symposia started in 1992 that are devoted to testing and fault-tolerant computing. ATS is now recognized as the primary event for covering many dimensions of testing for computing systems. Following tradition, this year’s ATS, organized by the Shanghai University, aims at providing a more open forum for worldwide researchers and industrial practitioners to exchange their innovative ideas on testing technology for both hardware and software in computing systems. The program of ATS 2010 consisted of two keynote speeches, multiple technical sessions, one panel session, and a special session that featured a doctoral thesis award. Ajay Bose (Atrenta) and R. Keith Lee (Advantest) delivered the keynote speeches. The panel session addressed the topic of “Testing Nanoelectronic Circuits under Massive Statistical Process Variations.”

UPCOMING TTTC EVENTS
29th VLSI Test Symposium (VTS 2011)
1–5 May 2011
Dana Point, California

The IEEE VLSI Test Symposium (VTS) explores emerging trends and novel concepts in testing, and verification/validation of microelectronic circuits and systems. In addition to the conventional technical program, VTS 2011 will provide special sessions, tutorials, and a workshop. There will be two tutorials. The first tutorial’s theme is “Advanced Topics and Recent Advances in Silicon Debug and Diagnosis”; the second tutorial’s theme is “Practices in Analog, Mixed-signal, and RF Testing.” Both tutorials will be held on 1 May.

The third IEEE Design for Reliability and Variability Workshop (DRV 2011) will be collocated. The TTTC Student Activities Committee is organizing two activities that will be aimed at providing graduate students with an opportunity to disseminate their research and obtain visibility in the international test community.

16th IEEE European Test Symposium (ETS 2011)
23–27 May 2011
Trondheim, Norway

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, practical applications, hot topics, and new trends in the area of electronic-based circuit and system testing. In 2011 ETS is being organized by the Norwegian University of Science and Technology (NTNU) and sponsored by the Test Technology Technical Council (TTTC) of the IEEE Computer Society. A Test Spring School will be organized in conjunction with ETS 2011.

There will be four workshops: “Dependability Issues in Deep-submicron Technologies,” “IEEE
International Workshop on Processor Verification, Test and Debug (IWPVT 2011); "The 2011 IEEE International Workshop on Memory Technology, Design and Test (MTDT 2011); and "Workshop on Low Power Design Impact on Test and Reliability (LPonTR)." ETS 2011 will also organize the TTTC's E.J. McCluskey Doctoral Thesis Award. ETS 2011 will offer commercial vendors the opportunity to give technical presentations during vendor sessions in a track that is parallel to the technical-paper sessions. These presentations will be listed in the symposium program along with the technical sessions, and should be targeted to the ETS technical audience. The vendor sessions differ from other ETS presentations in that company names, logos, and product names may be mentioned and displayed explicitly. Typical content includes product descriptions, case studies, best practices, and user testimonials.

Newsletter Editor's Invitation

I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Partha Pande, School of Electrical Engineering and Computer Science, Washington State University, PO Box 642752, Pullman, WA 99164-2752; pande@eecs.wsu.edu.

Partha Pande
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